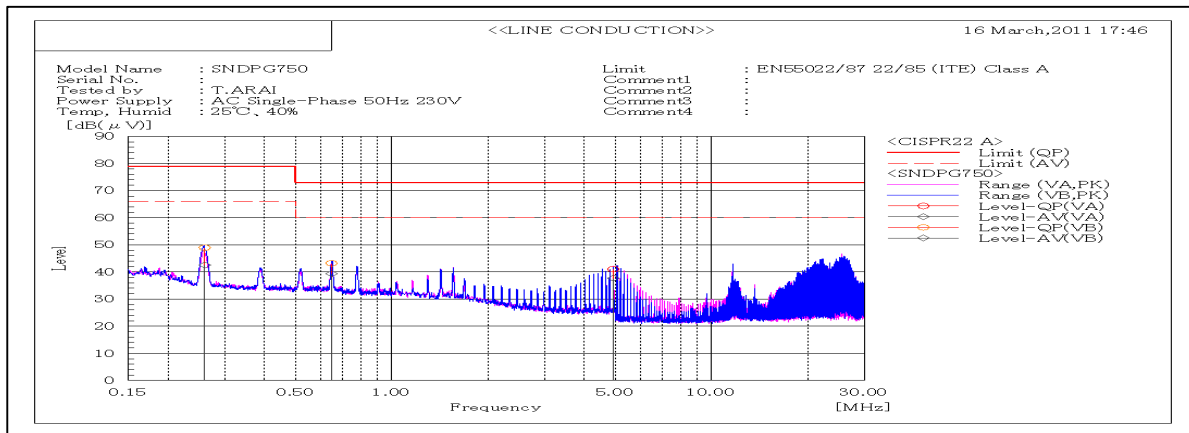
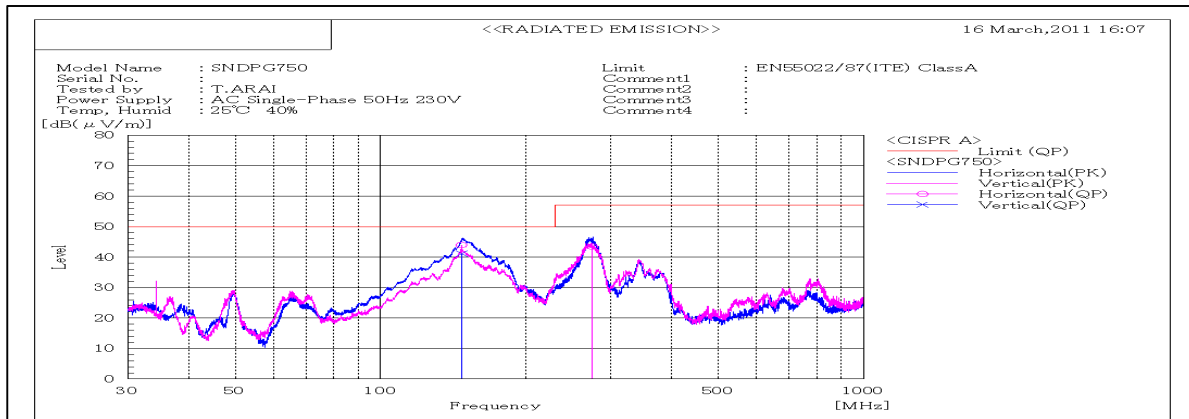


DATA SHEET		Date	26-Jul-11
Model	SNDPG750	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.ARAI



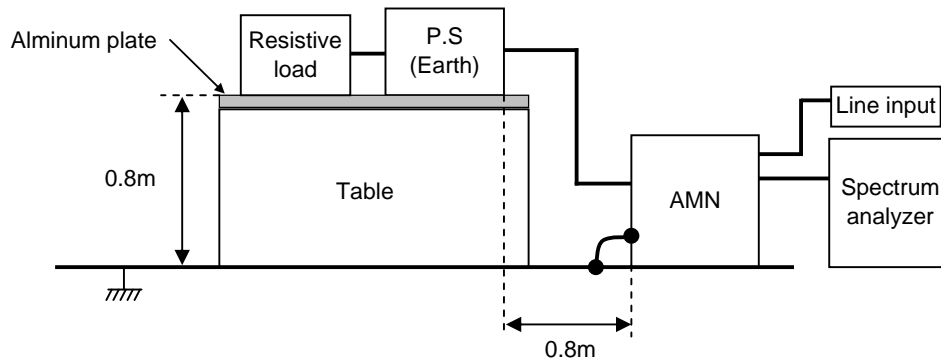
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.25979		VB	38.9	32.4	10.1	49	42.5	79	66	30	23.5	Pass	
0.64721		VB	33.1	29.3	10.1	43.2	39.4	73	60	29.8	20.6	Pass	
4.93255		VA	30.6	27.2	10.4	41	37.6	73	60	32	22.4	Pass	



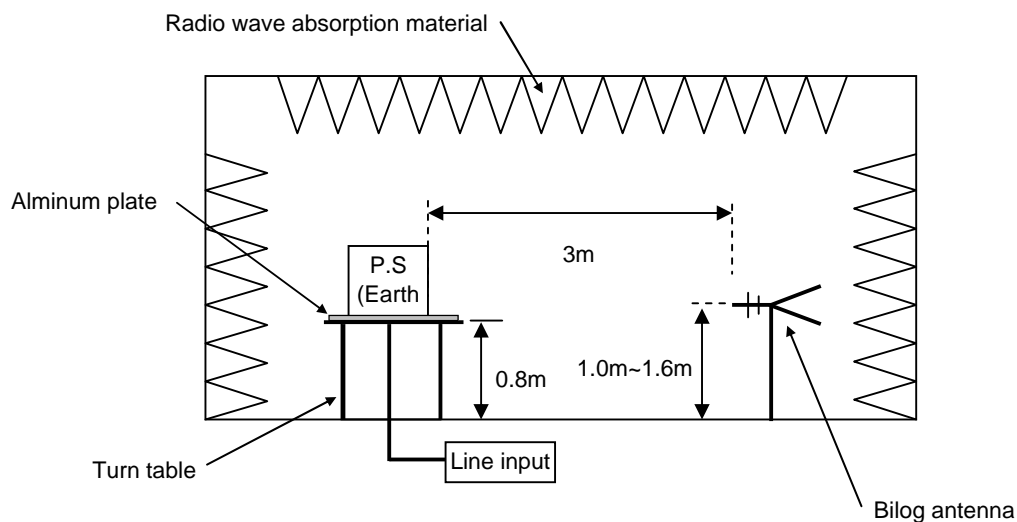
Frequency MHz	Polariz ation	Stability	Reading dB(μV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP		QP	QP					
147.021	H	Stable	64	-20.1	43.9	50	6.1	Pass	152	337	
147.29	V	Stable	61.2	-20.1	41.1	50	8.9	Pass	159	251	
274.353	H	Stable	61.5	-18.1	43.4	57	13.6	Pass	103	327	

DATA SHEET		Date	26-Jul-11
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.ARAI

1. Line conduction



2. Radiated emission

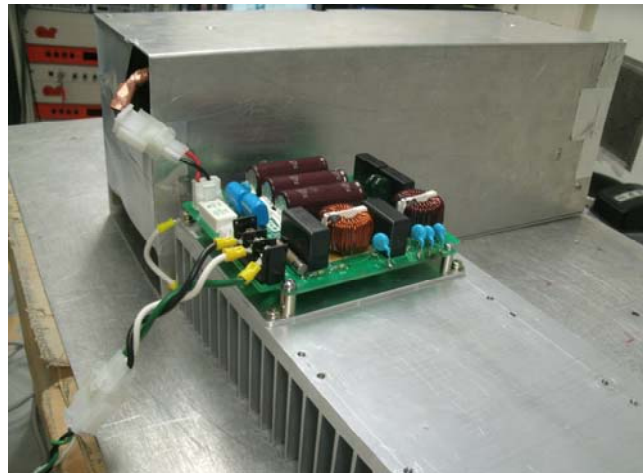


Test: EMI

Model Name: SNDPG750

○ Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION

